



## 74ABT245

# Octal Bi-Directional Transceiver with 3-STATE Outputs

### Features

- Bidirectional non-inverting buffers
- A and B output sink capability of 64mA, source capability of 32mA
- Guaranteed output skew
- Guaranteed multiple output switching specifications
- Output switching specified for both 50pF and 250pF loads
- Guaranteed simultaneous switching, noise level and dynamic threshold performance
- Guaranteed latchup protection
- High-impedance, glitch-free bus loading during entire power up and power down cycle
- Nondestructive, hot-insertion capability
- Disable time is less than enable time to avoid bus contention

### General Description

The ABT245 contains eight non-inverting bidirectional buffers with 3-STATE outputs and is intended for bus-oriented applications. Current sinking capability is 64 mA on both the A and B ports. The Transmit/Receive (T/R) input determines the direction of data flow through the bidirectional transceiver. Transmit (active HIGH) enables data from A Ports to B Ports; Receive (active LOW) enables data from B Ports to A Ports. The Output Enable input, when HIGH, disables both A and B ports by placing them in a HIGH Z condition.

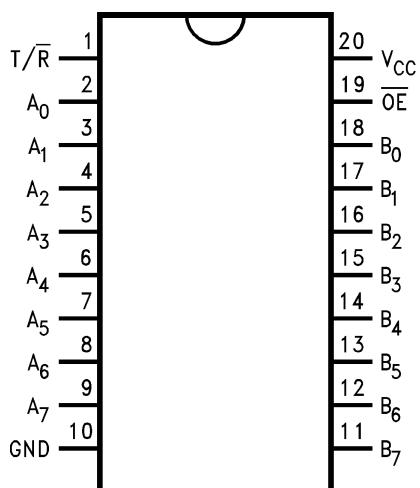
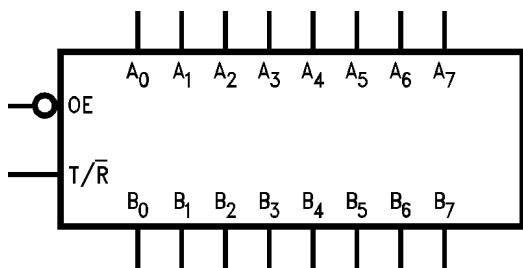
### Ordering Information

Order Number	Package Number	Package Description
74ABT245CSC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide
74ABT245CSJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74ABT245CMSA	MSA20	20-Lead Shrink Small Outline Package (SSOP), JEDEC MO-150, 5.3mm Wide
74ABT245CMTC	MTC20	20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide
74ABT245CMTCX_NL <sup>(1)</sup>	MTC20	20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide

Device also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering number.  
Pb-Free package per JEDEC J-STD-020B.

**Note:**

1. Device available in Tape and Reel only.

**Connection Diagram****Logic Symbol****Truth Table**

Inputs		Output
OE	T/R	
L	L	Bus B Data to Bus A
L	H	Bus A Data to Bus B
H	X	HIGH Z State

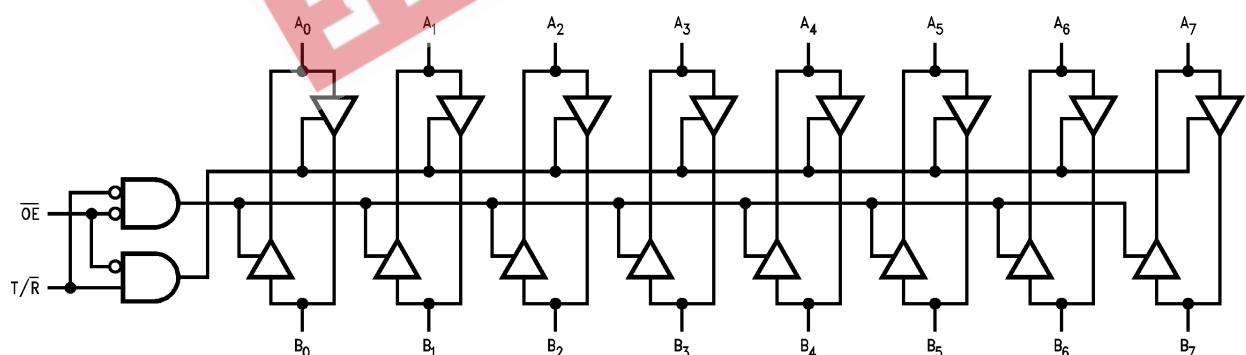
H = HIGH Voltage Level

L = LOW Voltage Level

X = Immaterial

**Pin Descriptions**

Pin Names	Description
OE	Output Enable Input (Active LOW)
T/R	Transmit/Receive Input
A <sub>0</sub> -A <sub>7</sub>	Side A Inputs or 3-STATE Outputs
B <sub>0</sub> -B <sub>7</sub>	Side B Inputs or 3-STATE Outputs

**Logic Diagram**

## Absolute Maximum Ratings

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Parameter	Rating
$T_{STG}$	Storage Temperature	-65°C to +150°C
$T_A$	Ambient Temperature Under Bias	-55°C to +125°C
$T_J$	Junction Temperature Under Bias	-55°C to +150°C
$V_{CC}$	$V_{CC}$ Pin Potential to Ground Pin	-0.5V to +7.0V
$V_{IN}$	Input Voltage <sup>(2)</sup>	-0.5V to +7.0V
$I_{IN}$	Input Current <sup>(2)</sup>	-30mA to +5.0mA
$V_O$	Voltage Applied to Any Output Disabled or Power-off State HIGH State	-0.5V to 5.5V -0.5V to $V_{CC}$
	Current Applied to Output in LOW State	twice the rated $I_{OL}$ (mA)
	DC Latchup Source Current	-500mA
	Over Voltage Latchup (I/O)	10V

**Note:**

2. Either voltage limit or current limit is sufficient to protect inputs.

## Recommended Operating Conditions

The Recommended Operating Conditions table defines the conditions for actual device operation. Recommended operating conditions are specified to ensure optimal performance to the datasheet specifications. Fairchild does not recommend exceeding them or designing to absolute maximum ratings.

Symbol	Parameter	Rating
$T_A$	Free Air Ambient Temperature	-40°C to +85°C
$V_{CC}$	Supply Voltage	+4.5V to +5.5V
$\Delta V / \Delta t$	Minimum Input Edge Rate Data Input Enable Input	50mV/ns 20mV/ns

## DC Electrical Characteristics

Symbol	Parameter	V <sub>CC</sub>	Conditions	Min.	Typ.	Max.	Units
V <sub>IH</sub>	Input HIGH Voltage		Recognized HIGH Signal	2.0			V
V <sub>IL</sub>	Input LOW Voltage		Recognized LOW Signal			0.8	V
V <sub>CD</sub>	Input Clamp Diode Voltage	Min.	I <sub>IN</sub> = -18 mA ( $\overline{OE}$ , T/R)			-1.2	V
V <sub>OH</sub>	Output HIGH Voltage	Min.	I <sub>OH</sub> = -3 mA (A <sub>n</sub> , B <sub>n</sub> )	2.5			V
		Min.	I <sub>OH</sub> = -32 mA (A <sub>n</sub> , B <sub>n</sub> )	2.0			
V <sub>OL</sub>	Output LOW Voltage	Min.	I <sub>OL</sub> = 64 mA (A <sub>n</sub> , B <sub>n</sub> )			0.55	V
I <sub>IH</sub>	Input HIGH Current	Max.	V <sub>IN</sub> = 2.7V ( $\overline{OE}$ , T/R)			1	$\mu A$
			V <sub>IN</sub> = V <sub>CC</sub> ( $\overline{OE}$ , T/R)			1	
I <sub>BVI</sub>	Input HIGH Current Breakdown Test	Max.	V <sub>IN</sub> = 7.0V ( $\overline{OE}$ , T/R)			7	$\mu A$
I <sub>BVIT</sub>	Input HIGH Current Breakdown Test (I/O)	Max.	V <sub>IN</sub> = 5.5V (A <sub>n</sub> , B <sub>n</sub> )			100	$\mu A$
I <sub>IL</sub>	Input LOW Current	Max.	V <sub>IN</sub> = 0.5V ( $\overline{OE}$ , T/R)			-1	$\mu A$
			V <sub>IN</sub> = 0.0V ( $\overline{OE}$ , T/R)			-1	
V <sub>ID</sub>	Input Leakage Test	0.0	I <sub>ID</sub> = 1.9 $\mu A$ ( $\overline{OE}$ , T/R), All Other Pins Grounded	4.75			V
I <sub>IH</sub> + I <sub>OZH</sub>	Output Leakage Current	0-5.5V	V <sub>OUT</sub> = 2.7V (A <sub>n</sub> , B <sub>n</sub> ), $\overline{OE}$ = 2.0V			10	$\mu A$
I <sub>IL</sub> + I <sub>OZL</sub>	Output Leakage Current	0-5.5V	V <sub>OUT</sub> = 0.5V (A <sub>n</sub> , B <sub>n</sub> ), $\overline{OE}$ = 2.0V			-10	$\mu A$
I <sub>OS</sub>	Output Short-Circuit Current	Max.	V <sub>OUT</sub> = 0.0V (A <sub>n</sub> , B <sub>n</sub> )	-100		-275	mA
I <sub>CEx</sub>	Output HIGH Leakage Current	Max.	V <sub>OUT</sub> = V <sub>CC</sub> (A <sub>n</sub> , B <sub>n</sub> )			50	$\mu A$
I <sub>ZZ</sub>	Bus Drainage Test	0.0	V <sub>OUT</sub> = 5.5V (A <sub>n</sub> , B <sub>n</sub> ), All Others GND			100	$\mu A$
I <sub>CCH</sub>	Power Supply Current	Max.	All Outputs HIGH			50	$\mu A$
I <sub>CCL</sub>	Power Supply Current	Max.	All Outputs LOW			30	mA
I <sub>CCZ</sub>	Power Supply Current	Max.	$\overline{OE}$ = V <sub>CC</sub> , T/R = GND or V <sub>CC</sub> , All Other GND or V <sub>CC</sub>			50	$\mu A$
I <sub>CCT</sub>	Additional I <sub>CC</sub> /Input	Outputs Enabled	Max.	V <sub>I</sub> = V <sub>CC</sub> - 2.1V		2.5	mA
		Outputs 3-STATE		$\overline{OE}$ , T/R V <sub>I</sub> = V <sub>CC</sub> - 2.1V		2.5	mA
		Outputs 3-STATE		Data Input V <sub>I</sub> = V <sub>CC</sub> - 2.1V, All Others at V <sub>CC</sub> or GND.		50	$\mu A$
I <sub>CCD</sub>	Dynamic I <sub>CC</sub> No Load	Max.	Outputs Open, $\overline{OE}$ = GND, T/R = GND or V <sub>CC</sub> , One Bit Toggling, 50% Duty Cycle			0.1	mA/MHz

## DC Electrical Characteristics

SOIC package.

Symbol	Parameter	V <sub>CC</sub>	Conditions C <sub>L</sub> = 50 pF, R <sub>L</sub> = 500Ω	Min.	Typ.	Max.	Units
V <sub>OLP</sub>	Quiet Output Maximum Dynamic V <sub>OL</sub>	5.0	T <sub>A</sub> = 25°C <sup>(3)</sup>		0.7	1.0	V
V <sub>OLV</sub>	Quiet Output Minimum Dynamic V <sub>OL</sub>	5.0	T <sub>A</sub> = 25°C <sup>(3)</sup>	-1.3	-1.0		V
V <sub>OHV</sub>	Minimum HIGH Level Dynamic Output Voltage	5.0	T <sub>A</sub> = 25°C <sup>(5)</sup>	2.7	3.1		V
V <sub>IHD</sub>	Minimum HIGH Level Dynamic Input Voltage	5.0	T <sub>A</sub> = 25°C <sup>(4)</sup>	2.0	1.7		V
V <sub>ILD</sub>	Maximum LOW Level Dynamic Input Voltage	5.0	T <sub>A</sub> = 25°C <sup>(4)</sup>		0.9	0.6	V

**Notes:**

3. Max number of outputs defined as (n). n-1 data inputs are driven 0V to 3V. One output at LOW. Guaranteed, but not tested.
4. Max number of data inputs (n) switching. n-1 inputs switching 0V to 3V. Input-under-test switching: 3V to threshold (V<sub>ILD</sub>), 0V to threshold (V<sub>IHD</sub>). Guaranteed, but not tested.
5. Max number of outputs defined as (n). n – 1 data inputs are driven 0V to 3V. One output HIGH. Guaranteed, but not tested.

## AC Electrical Characteristics

SOIC and SSOP package.

Symbol	Parameter	T <sub>A</sub> = +25°C, V <sub>CC</sub> = +5V, C <sub>L</sub> = 50pF			T <sub>A</sub> = -55°C to +125°C, V <sub>CC</sub> = 4.5V to 5.5V, C <sub>L</sub> = 50pF			Units	
		Min.	Typ.	Max.	Min.	Max.	Min.		
t <sub>PLH</sub>	Propagation Delay, Data to Outputs	1.0	2.1	3.6	1.0	4.8	1.0	3.6	ns
		1.0	2.4	3.6	1.0	4.8	1.0	3.6	
t <sub>PHL</sub>	Output Enable Time	1.5	3.2	6.0	1.0	6.7	1.5	6.0	ns
		1.5	3.7	6.0	2.0	7.5	1.5	6.0	
t <sub>PZH</sub>	Output Disable Time	1.0	3.6	6.1	1.7	7.4	1.0	6.1	ns
		1.0	3.3	5.6	1.7	6.5	1.0	5.6	

### Extended AC Electrical Characteristics

SOIC package.

Symbol	Parameter	$T_A = -40^\circ\text{C to } +85^\circ\text{C}$ , $V_{CC} = 4.5\text{V to } 5.5\text{V}$ , $C_L = 50\text{pF}$ , 8 Outputs Switching <sup>(6)</sup>			$T_A = -40^\circ\text{C to } +85^\circ\text{C}$ , $V_{CC} = 4.5\text{V to } 5.5\text{V}$ , $C_L = 250\text{pF}$ , 1 Output Switching <sup>(7)</sup>			$T_A = -40^\circ\text{C to } +85^\circ\text{C}$ , $V_{CC} = 4.5\text{V to } 5.5\text{V}$ , $C_L = 250\text{pF}$ , 8 Outputs Switching <sup>(8)</sup>			Units
		Min.	Typ.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
$f_{TOGGLE}$	Max Toggle Frequency		100								MHz
$t_{PLH}$	Propagation Delay	1.5		5.0	1.5	6.0	2.5	8.5			ns
$t_{PHL}$	Data to Outputs	1.5		5.0	1.5	6.0	2.5	8.5			ns
$t_{PZH}$	Output Enable Time	1.5		6.5	2.5	7.5	2.5	9.5			ns
$t_{PZL}$	Output Disable Time	1.5		6.5	2.5	7.5	2.5	11.0			ns
$t_{PHZ}$		1.0		6.5	(9)			(9)			ns
$t_{PLZ}$		1.0		5.6							

**Notes:**

6. This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.).
7. This specification is guaranteed but not tested. The limits represent propagation delay with 250pF load capacitors in place of the 50pF load capacitors in the standard AC load. This specification pertains to single output switching only.
8. This specification is guaranteed but not tested. The limits represent propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.) with 250pF load capacitors in place of the 50pF load capacitors in the standard AC load.
9. The 3-STATE delays are dominated by the RC network ( $500\Omega$ , 250pF) on the output and have been excluded from the datasheet.

## Skew

SOIC package.

Symbol	Parameter	$T_A = -40^\circ\text{C to } +85^\circ\text{C}$ , $V_{CC} = 4.5\text{V to } 5.5\text{V}$ , $C_L = 50\text{pF}$ , 8 Outputs Switching <sup>(12)</sup>	$T_A = -40^\circ\text{C to } +85^\circ\text{C}$ , $V_{CC} = 4.5\text{V to } 5.5\text{V}$ , $C_L = 250\text{pF}$ , 8 Outputs Switching <sup>(13)</sup>	Units
		Max.	Max.	
$t_{OSHL}^{(10)}$	Pin to Pin Skew, HL Transitions	1.3	2.3	ns
$t_{OSLH}^{(10)}$	Pin to Pin Skew, LH Transitions	1.0	1.8	ns
$t_{PS}^{(14)}$	Duty Cycle, LH–HL Skew	2.0	3.5	ns
$t_{OST}^{(10)}$	Pin to Pin Skew, LH/HL Transitions	2.0	3.5	ns
$t_{PV}^{(11)}$	Device to Device Skew, LH/HL Transitions	2.0	3.5	ns

### Notes:

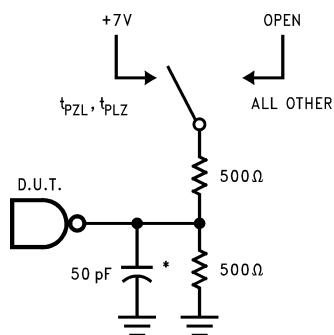
10. Skew is defined as the absolute value of the difference between the actual propagation delays for any two separate outputs of the same device. The specification applies to any outputs switching HIGH-to-LOW ( $t_{OSHL}$ ), LOW-to-HIGH ( $t_{OSLH}$ ), or any combination switching LOW-to-HIGH and/or HIGH-to-LOW ( $t_{OST}$ ). The specification is guaranteed but not tested.
11. Propagation delay variation for a given set of conditions (i.e., temperature and  $V_{CC}$ ) from device to device. This specification is guaranteed but not tested.
12. This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.)
13. These specifications guaranteed but not tested. The limits represent propagation delays with 250pF load capacitors in place of the 50pF load capacitors in the standard AC load.
14. This describes the difference between the delay of the LOW-to-HIGH and the HIGH-to-LOW transition on the same pin. It is measured across all the outputs (drivers) on the same chip, the worst (largest delta) number is the guaranteed specification. This specification is guaranteed but not tested.

## Capacitance

Symbol	Parameter	Conditions $T_A = 25^\circ\text{C}$	Typ.	Units
$C_{IN}$	Input Capacitance	$V_{CC} = 0\text{V}$ ( $\overline{OE}, \overline{T/R}$ )	5.0	pF
$C_{I/O}^{(15)}$	I/O Capacitance	$V_{CC} = 5.0\text{V}$ ( $A_n, B_n$ )	11.0	pF

### Note:

15.  $C_{I/O}$  is measured at frequency  $f = 1$  MHz, per MIL-STD-883, Method 3012.

**AC Loading**

\*Includes jig and probe capacitance

Figure 1. Standard AC Test Load

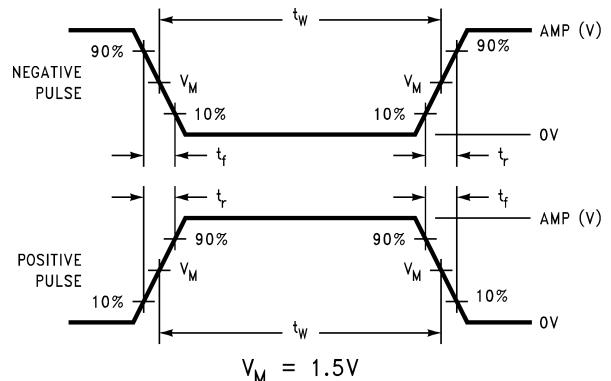


Figure 2. Test Input Signal Levels

Amplitude	Rep. Rate	$t_W$	$t_r$	$t_f$
3.0V	1MHz	500ns	2.5ns	2.5ns

Figure 3. Test Input Signal Requirements

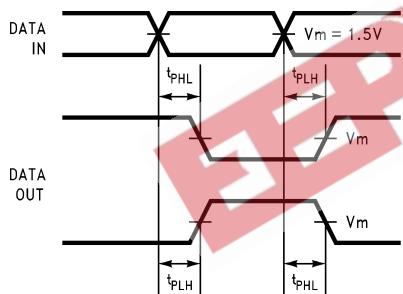
**AC Waveforms**

Figure 4. Propagation Delay Waveforms for Inverting and Non-Inverting Functions

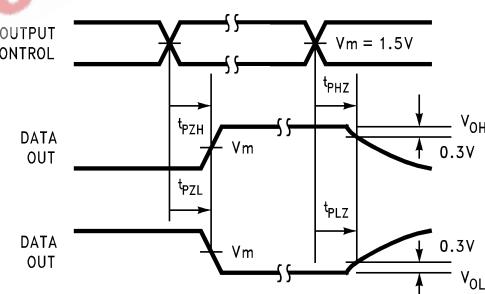


Figure 6. 3-STATE Output HIGH and LOW Enable and Disable Times

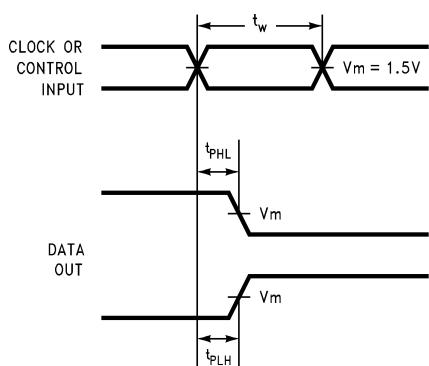


Figure 5. Propagation Delay, Pulse Width Waveforms

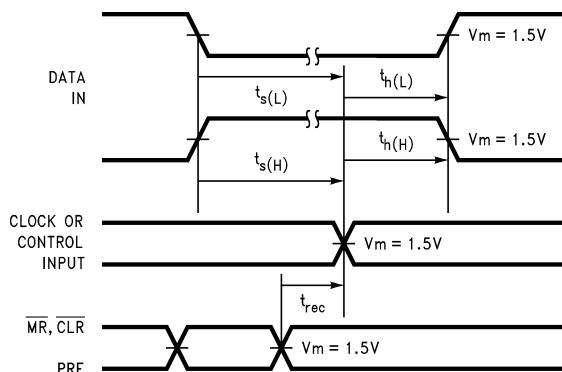


Figure 7. Setup Time, Hold Time and Recovery Time Waveforms

## Physical Dimensions

Dimensions are in inches (millimeters) unless otherwise noted.

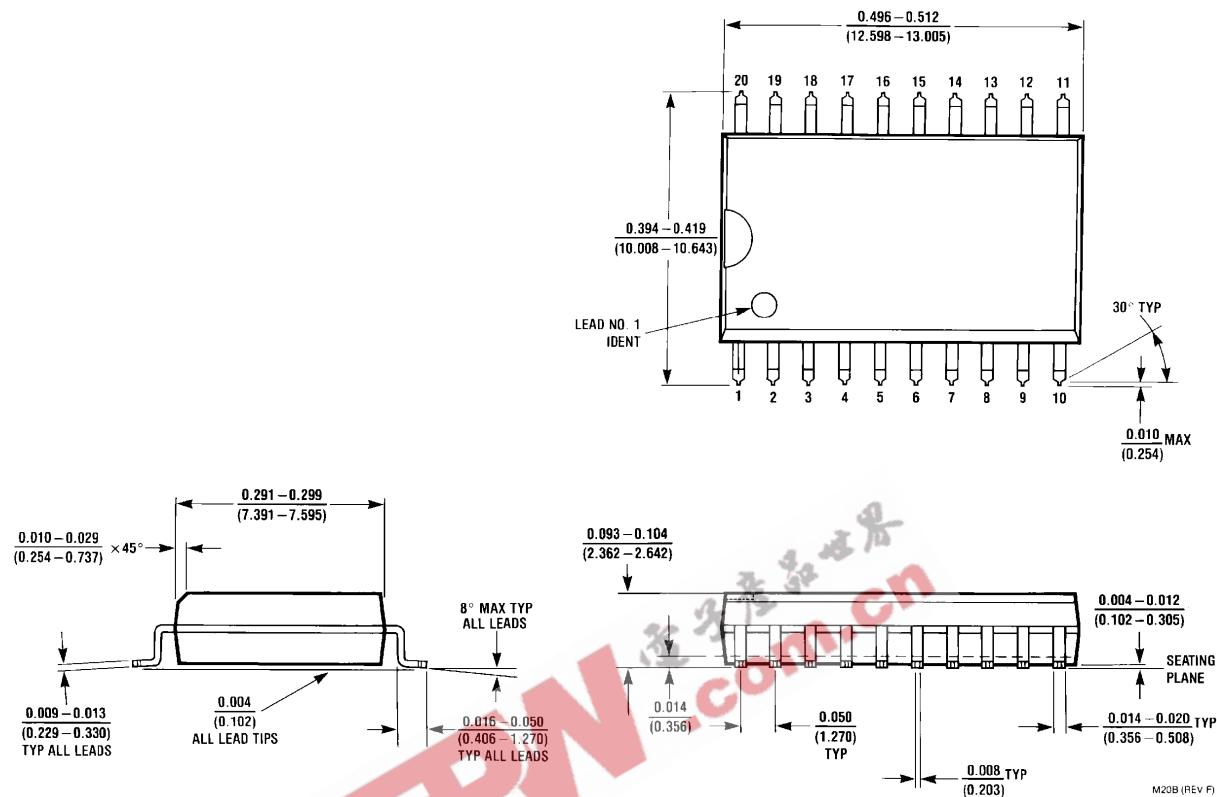
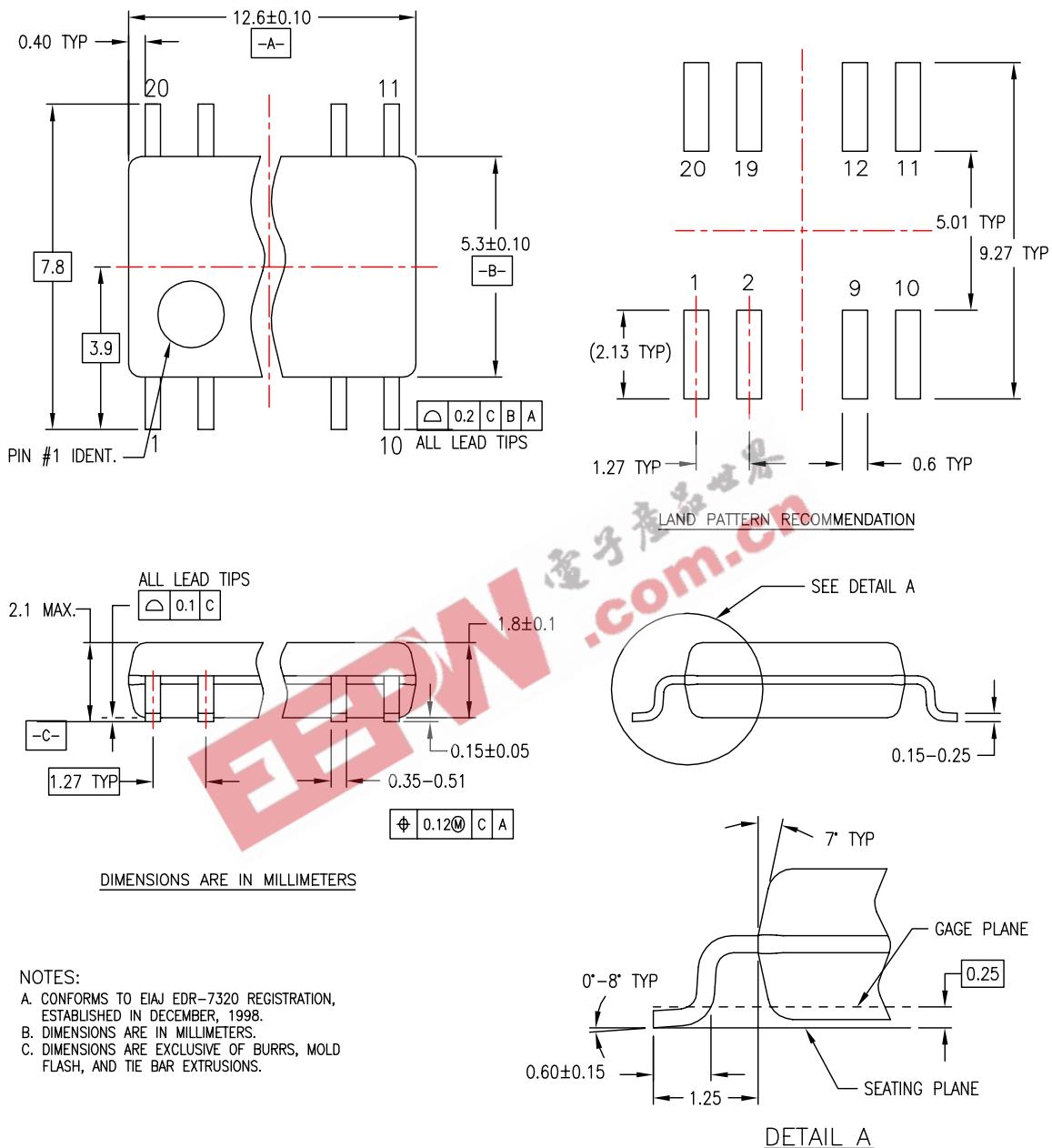


Figure 8. 20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide  
Package Number M20B

## Physical Dimensions (Continued)

Dimensions are in millimeters unless otherwise noted.

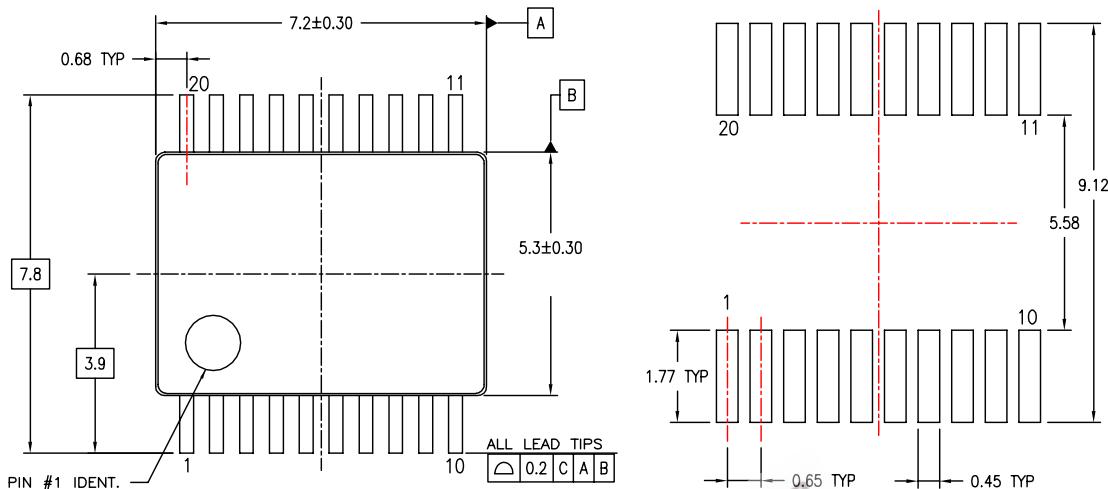


M20DREVC

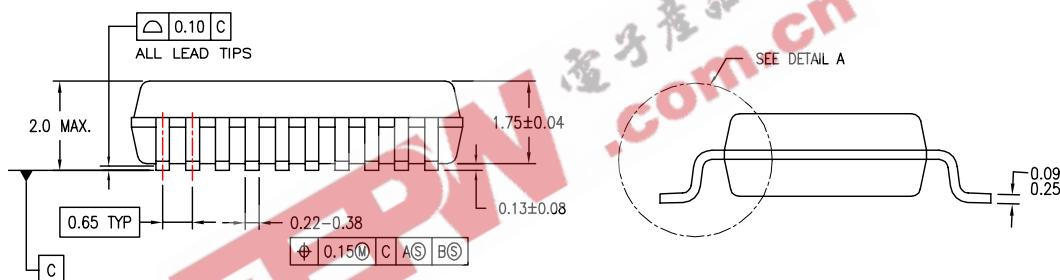
**Figure 9. 20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide  
Package Number M20D**

## Physical Dimensions (Continued)

Dimensions are in millimeters unless otherwise noted.



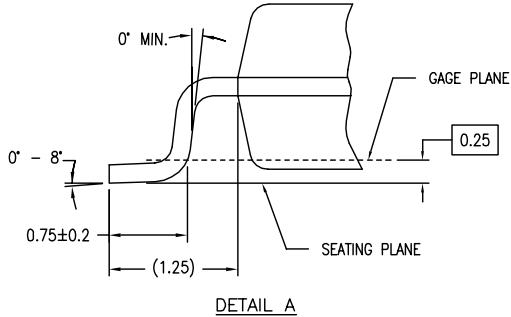
### LAND PATTERN RECOMMENDATIONS



DIMENSIONS ARE IN MILLIMETERS

### NOTES:

- A. CONFORMS TO JEDEC REGISTRATION MO-150, VARIATION AE, DATE 1/94.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- D. DIMENSIONS AND TOLERANCES PER ASME Y14.5M - 1994.

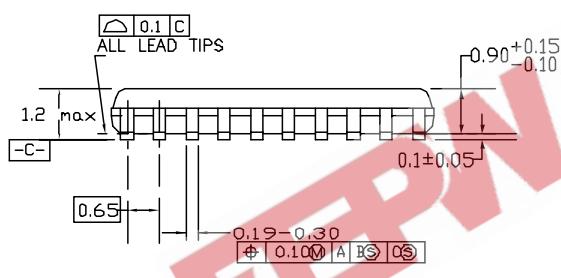
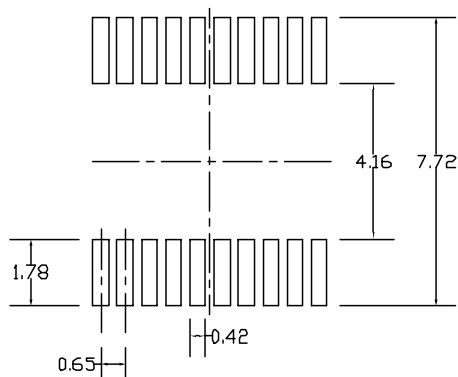
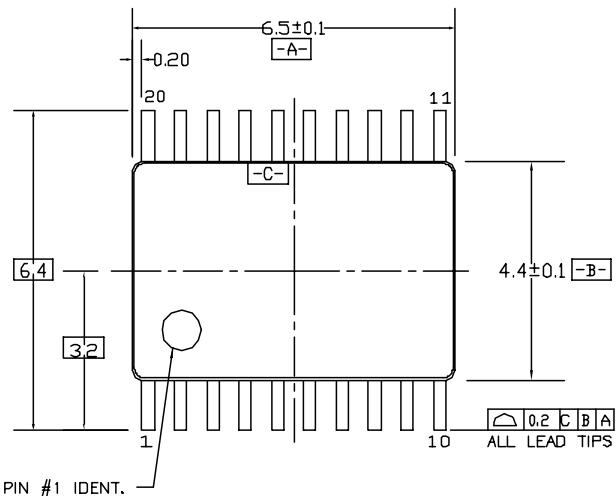


MSA20REVB

Figure 10. 20-Lead Shrink Small Outline Package (SSOP), JEDEC MO-150, 5.3mm Wide  
Package Number MSA20

## Physical Dimensions (Continued)

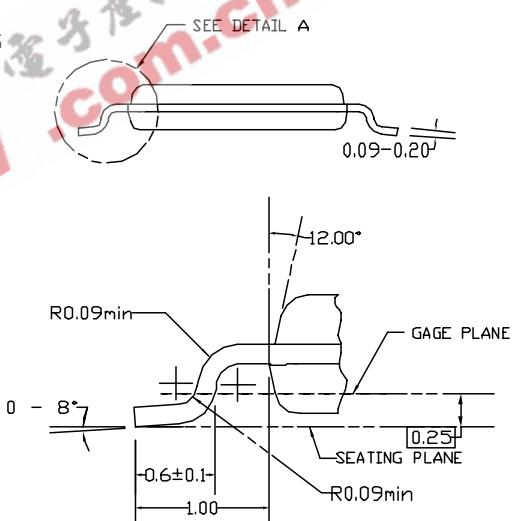
Dimensions are in millimeters unless otherwise noted.



DIMENSIONS ARE IN MILLIMETERS

### NOTES:

- CONFORMS TO JEDEC REGISTRATION MO-153, VARIATION AC, REF NOTE 6, DATE 7/93.
- DIMENSIONS ARE IN MILLIMETERS.
- DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLDS FLASH, AND TIE BAR EXTRUSIONS.
- DIMENSIONS AND TOLERANCES PER ANSI Y14.5M, 1982.



MTC20REV D1

**Figure 11. 20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide Package Number MTC20**



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CoolFET™	MICROCOUPLER™	RapidConfigure™	µSerDes™
CROSSVOLT™	MicroPak™	RapidConnect™	UHC®
CTL™	MICROWIRE™	ScalarPump™	UniFET™
Current Transfer Logic™	MSX™	SMART START™	VCX™
DOME™	MSXPro™	SPM®	Wire™
E <sup>2</sup> CMOS™	OCX™	STEALTH™	
EcoSPARK®	OCXPro™	SuperFET™	
EnSigna™	OPTOLOGIC®	SuperSOT™-3	
FACT Quiet Series™	OPTOPLANAR®	SuperSOT™-6	
FACT®	PACMAN™	SuperSOT™-8	
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As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
2. A critical component in any component of a life support device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

## PRODUCT STATUS DEFINITIONS

### Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild Semiconductor. The datasheet is printed for reference information only.

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